# **Power MOSFET**

# 30 V, 64 A, Single N-Channel, SO-8FL

#### **Features**

- Low R<sub>DS(ON)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Low R<sub>G</sub>
- These are Pb-Free Devices\*

## **Applications**

- CPU Power Delivery
- DC-DC Converters

## MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	30	V
Gate-to-Source Vol	Gate-to-Source Voltage			±20	V
Continuous Drain Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	I <sub>D</sub>	15 11	A
Power Dissipation R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	P <sub>D</sub>	2.17 1.13	W
Continuous Drain Current R <sub>θJA</sub> - t≤10 sec		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	I <sub>D</sub>	24 17	А
Power Dissipation $R_{\theta JA} t \le 10 \text{ sec}$	Steady State	T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	$P_{D}$	5.7 2.9	W
Continuous Drain Current R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	Ι <sub>D</sub>	9.5 7.0	A
Power Dissipation R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	P <sub>D</sub>	0.87 0.45	W
Continuous Drain Current R <sub>θJC</sub> (Note 1)		$T_C = 25^{\circ}C$ $T_C = 85^{\circ}C$	Ι <sub>D</sub>	64 46	A
Power Dissipation R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C T <sub>C</sub> = 25°C	P <sub>D</sub>	42.4 22	W
Pulsed Drain Current	t <sub>p</sub>	= 25°C, = 10 μs	I <sub>DM</sub>	192	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C
Source Current (Body Diode)			I <sub>S</sub>	35	Α
Drain to Source dV/dt			dV/dt	6	V/ns
Single Pulse Drain-to-Source Avalanche Energy ( $T_J$ = 25°C, $V_{DD}$ = 24 V, $V_{GS}$ = 10 V, $I_L$ = 27 A, L = 0.3 mH, $R_G$ = 25 $\Omega$ )			EAS	109	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

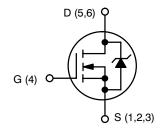
1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.



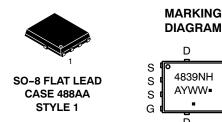
## ON Semiconductor®

## http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
22.1	5.5 mΩ @ 10 V	
30 V	10.3 m $\Omega$ @ 4.5 V	64 A



**N-CHANNEL MOSFET** 



= Assembly Location

= Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NTMFS4839NHT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4839NHT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

<sup>2.</sup> Surface-mounted on FR4 board using the minimum recommended pad size. \*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.95	
Junction-to-Ambient - Steady State (Note 3)	$R_{ heta JA}$	57.6	°C/W
Junction-to-Ambient - Steady State (Note 4)	$R_{ heta JA}$	143.3	-0/00
Junction-to-Ambient (t≤10 sec)	$R_{\theta JA}$	22	

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						1
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS}$ = 0 V, $I_D$ = 250 $\mu A$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				27.5		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25 °C			1	
			T <sub>J</sub> = 125°C			10	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)				•			•
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D =$	= 250 μΑ	1.5	2.1	2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.5		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V to 11.5 V	I <sub>D</sub> = 30 A		4.3	5.5	mΩ
			I <sub>D</sub> = 15 A		4.3		
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		8.2	10.3	
			I <sub>D</sub> = 15 A		7.8		
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 50 A			60		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE						
Input Capacitance	C <sub>ISS</sub>				1744	2354	
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 12 V			355	479	pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				191	296	
Total Gate Charge	Q <sub>G(TOT)</sub>				12.9	19.5	nC
Threshold Gate Charge	Q <sub>G(TH)</sub>		5 ) (   00 A		2.2	3.3	
Gate-to-Source Charge	$Q_{GS}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 1$	5 V; I <sub>D</sub> = 30 A		5.2	7.8	
Gate-to-Drain Charge	$Q_{GD}$				5.4	8.0	1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 11.5 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			31	43.5	nC
SWITCHING CHARACTERISTICS (Note 6)							
Turn-On Delay Time	t <sub>d(ON)</sub>				13.4	20	
Rise Time	t <sub>r</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			22.5	33.7	ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				16	24	
Fall Time	t <sub>f</sub>				5.3	7.9	

<sup>5.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.

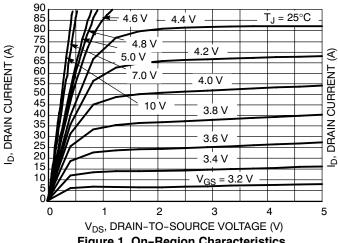
Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

<sup>6.</sup> Switching characteristics are independent of operating junction temperatures.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (No	te 6)						
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 11.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			8.1	12.2	ns
Rise Time	t <sub>r</sub>				19.6	29.4	
Turn-Off Delay Time	t <sub>d(OFF)</sub>				23.2	34.9	
Fall Time	t <sub>f</sub>				3.4	5.1	
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>SD</sub> V <sub>GS</sub> = 0 V, I <sub>S</sub> = 30 A	T <sub>J</sub> = 25°C		0.83	1.2	· v
			T <sub>J</sub> = 125°C		0.73		
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 30 A			19.3		ns
Charge Time	t <sub>a</sub>				10.1		
Discharge Time	t <sub>b</sub>				9.2		
Reverse Recovery Charge	$Q_{RR}$				6.3		nC
PACKAGE PARASITIC VALUES				-			
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			0.93		nH
Drain Inductance	L <sub>D</sub>				0.005		nH
Gate Inductance	L <sub>G</sub>				1.84		nH
Gate Resistance	R <sub>G</sub>				0.9		Ω

<sup>5.</sup> Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.



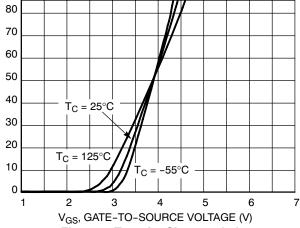
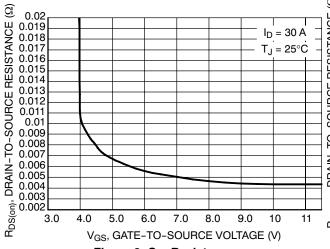


Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



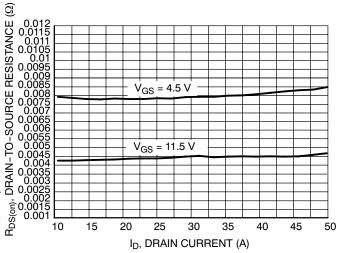
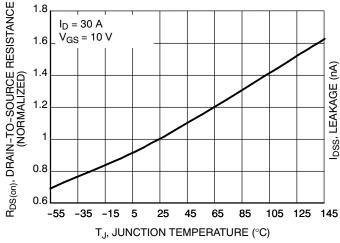


Figure 3. On-Resistance versus Gate-to-Source Voltage

Figure 4. On-Resistance versus Drain Current and Gate Voltage



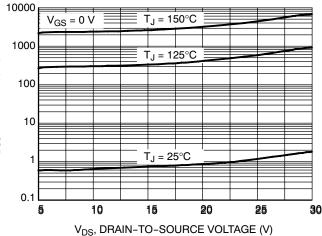


Figure 5. On-Resistance Variation with **Temperature** 

Figure 6. Drain-to-Source Leakage Current versus Voltage

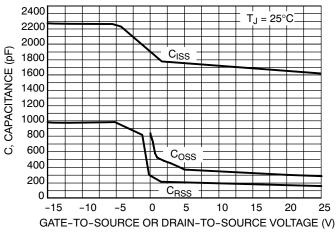


Figure 7. Capacitance Variation

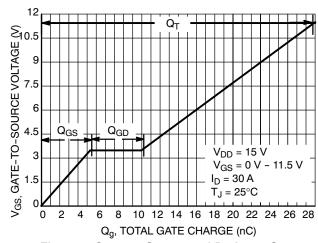


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Gate Charge

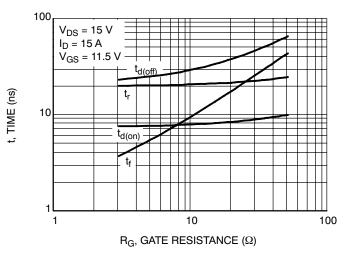


Figure 9. Resistive Switching Time Variation versus Gate Resistance

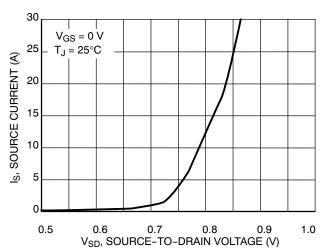


Figure 10. Diode Forward Voltage versus Current

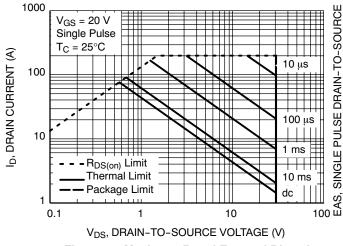


Figure 11. Maximum Rated Forward Biased Safe Operating Area

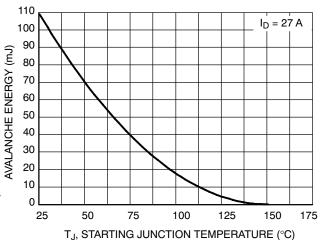


Figure 12. Maximum Avalanche Energy versus Starting Junction Temperature

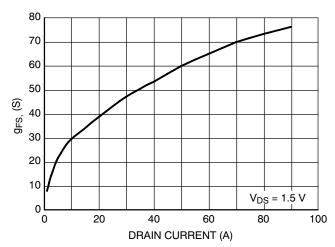
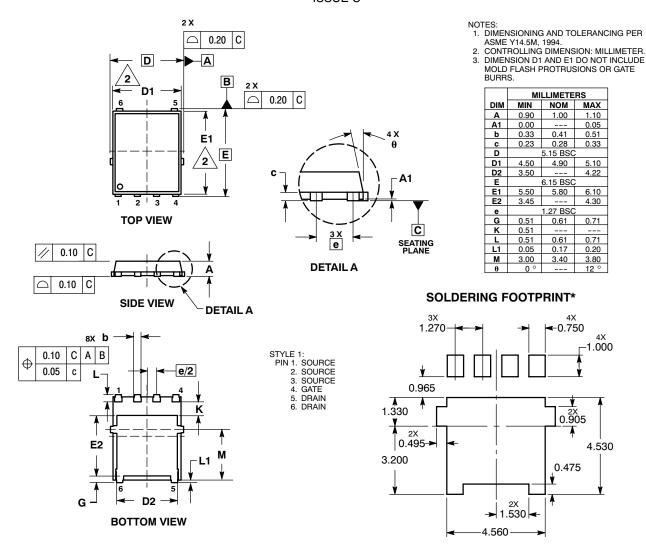


Figure 13.  $G_{FS}$  versus Drain Current

## PACKAGE DIMENSIONS

## DFN6 5x6, 1.27P (SO8 FL) CASE 488AA-01 ISSUE C



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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